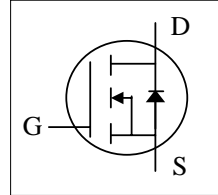




- ▼ Lower On-resistance
- ▼ Simple Drive Requirement
- ▼ Fast Switching Characteristic

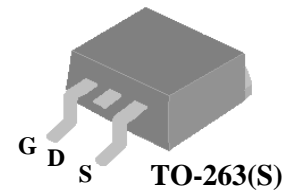


BV_{DSS}	40V
$R_{DS(ON)}$	7m Ω
I_D	80A

Description

Advanced Power MOSFETs from APEC provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-263 package is widely preferred for commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	40	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D@T_C=25^\circ C$	Continuous Drain Current ³	80	A
$I_D@T_C=100^\circ C$	Continuous Drain Current	55	A
I_{DM}	Pulsed Drain Current ¹	320	A
$P_D@T_C=25^\circ C$	Total Power Dissipation	89	W
	Linear Derating Factor	0.7	W/ $^\circ C$
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ C$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ C$

Thermal Data

Symbol	Parameter	Value	Units
Rthj-c	Maximum Thermal Resistance, Junction-case	1.4	$^\circ C/W$
Rthj-a	Maximum Thermal Resistance, Junction-ambient (PCB mount) ⁴	40	$^\circ C/W$


Electrical Characteristics @ $T_j=25^{\circ}\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	40	-	-	V
$\Delta BV_{DSS}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to $25^{\circ}\text{C}, I_D=250\mu A$	-	0.01	-	$V/^{\circ}\text{C}$
$R_{DS(ON)}$	Static Drain-Source On-Resistance ²	$V_{GS}=10V, I_D=45A$	-	-	7	m Ω
		$V_{GS}=4.5V, I_D=30A$	-	-	9	m Ω
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	0.5	-	1.5	V
g_{fs}	Forward Transconductance	$V_{DS}=10V, I_D=30A$	-	75	-	S
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=40V, V_{GS}=0V$	-	-	1	μA
	Drain-Source Leakage Current ($T_j=125^{\circ}\text{C}$)	$V_{DS}=32V, V_{GS}=0V$	-	-	250	μA
I_{GSS}	Gate-Source Leakage	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_D=30A$	-	36	58	nC
Q_{gs}	Gate-Source Charge	$V_{DS}=30V$	-	4	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{GS}=4.5V$	-	20	-	nC
$t_{d(on)}$	Turn-on Delay Time ²	$V_{DS}=20V$	-	8	-	ns
t_r	Rise Time	$I_D=30A$	-	62	-	ns
$t_{d(off)}$	Turn-off Delay Time	$R_G=1.0\Omega, V_{GS}=10V$	-	36	-	ns
t_f	Fall Time	$R_D=0.67\Omega$	-	16	-	ns
C_{iss}	Input Capacitance	$V_{GS}=0V$	-	2235	3580	pF
C_{oss}	Output Capacitance	$V_{DS}=25V$	-	365	-	pF
C_{rss}	Reverse Transfer Capacitance	$f=1.0\text{MHz}$	-	325	-	pF
R_g	Gate Resistance	$f=1.0\text{MHz}$	-	1.8	2.7	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_S=30A, V_{GS}=0V$	-	-	1.2	V
t_{rr}	Reverse Recovery Time ²	$I_S=20A, V_{GS}=0V,$	-	38	-	ns
Q_{rr}	Reverse Recovery Charge	$dI/dt=100A/\mu s$	-	30	-	nC

Notes:

1. Pulse width limited by Max. junction temperature.
2. Pulse test
3. Package limitation current is 80A .
4. Surface mounted on 1 in² copper pad of FR4 board

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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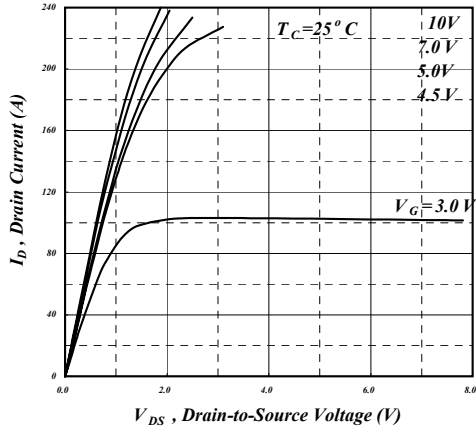


Fig 1. Typical Output Characteristics

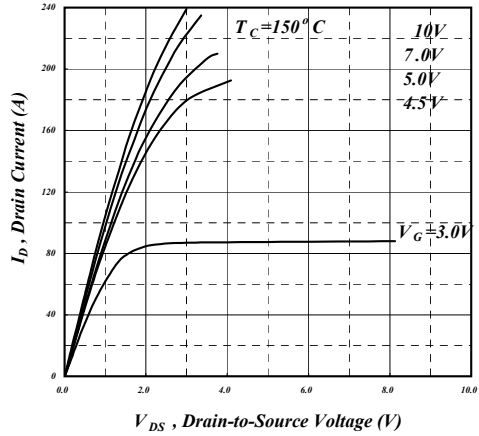


Fig 2. Typical Output Characteristics

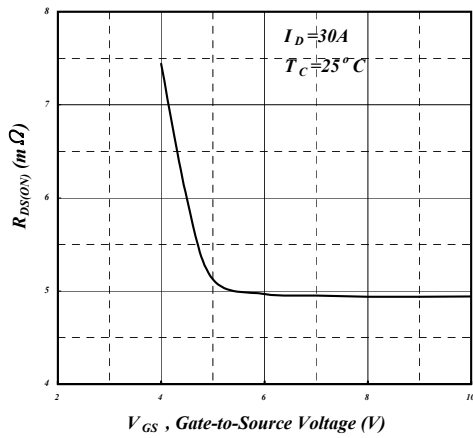


Fig 3. On-Resistance v.s. Gate Voltage

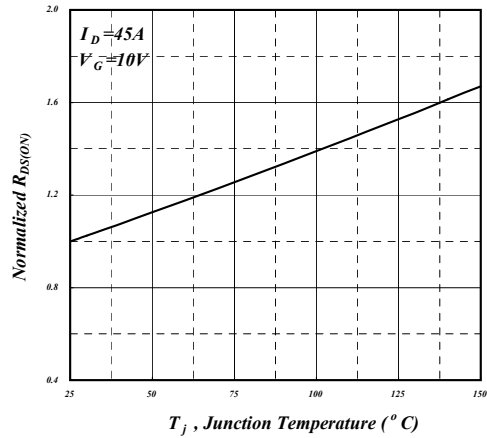


Fig 4. Normalized On-Resistance v.s. Junction Temperature

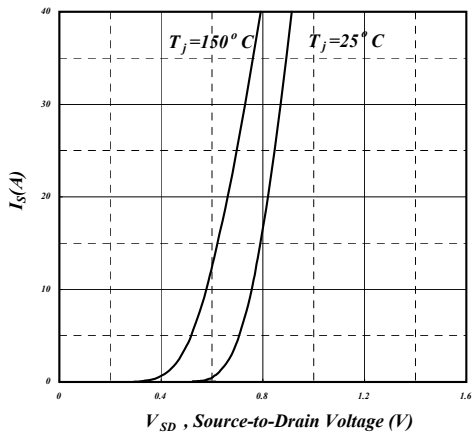


Fig 5. Forward Characteristic of Reverse Diode

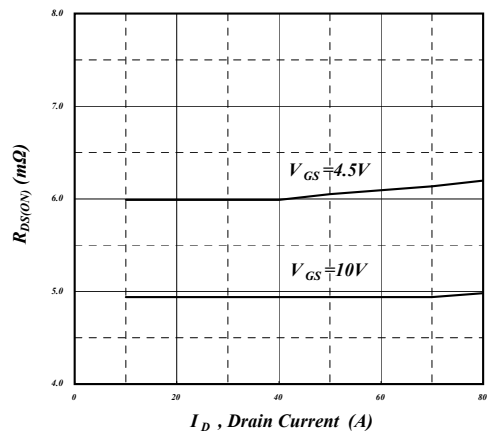


Fig 6. On-Resistance vs. Drain Current

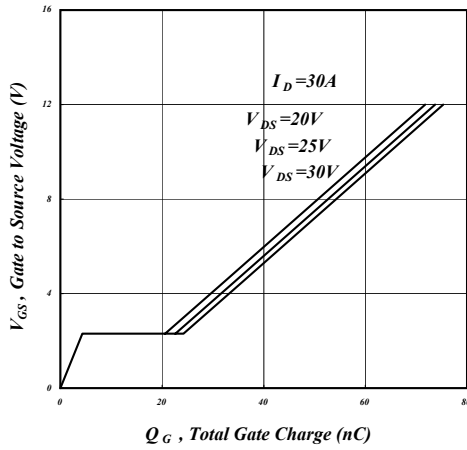


Fig 7. Gate Charge Characteristics

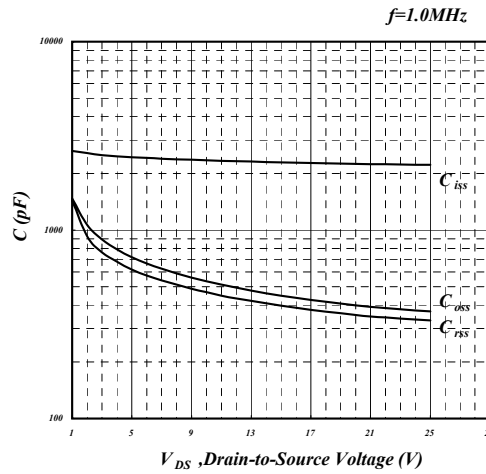


Fig 8. Typical Capacitance Characteristics

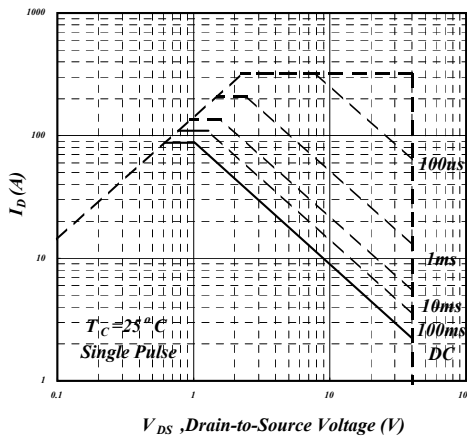


Fig 9. Maximum Safe Operating Area

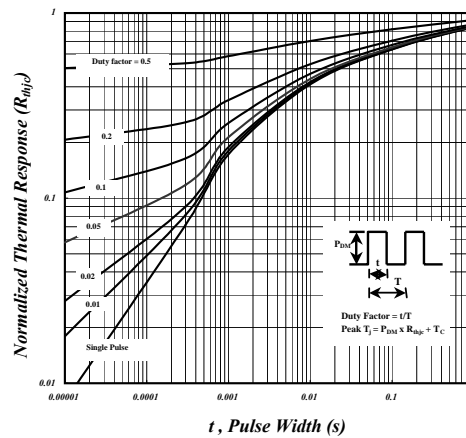


Fig 10. Effective Transient Thermal Impedance

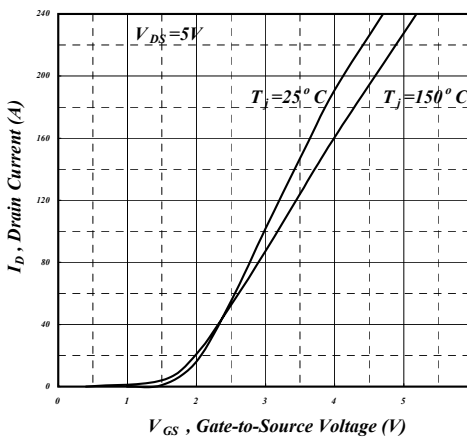


Fig 11. Transfer Characteristics

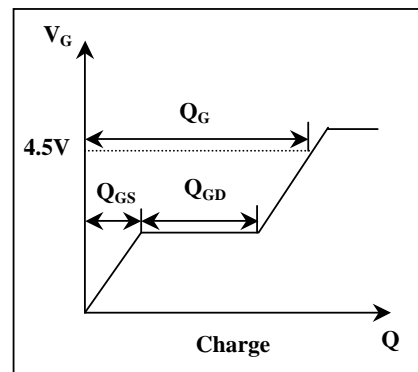


Fig 12. Gate Charge Waveform